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<b>Notice of References Cited</b>	Application/Control No. 09/215,194	Applicant(s)/Patent Under Reexamination IKEGAMI ET AL.	
	Examiner Tanh Q. Nguyen	Art Unit 2182	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,134,711 A	10-2000	Nakamura et al.	717/169
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08212079 A	08-1996	JP	Senma	G06F 009/445
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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